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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10028910	12/28/2001	435	6	11024	FORMAN 77141

**APPLICANTS: Nagasawa Hiroshi;

**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

JAPAN 402451/2000 12/28/2000

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed	<input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO	
35 USC 119 conditions met	<input type="checkbox"/> yes <input type="checkbox"/> no	NAGASAWA=6	
Verified and Acknowledged Examiner's initials			
TITLE : Affinity detecting/analytical chip, method for production thereof, detection method and detection system using same			

U.S. DEPT. OF COMM./PAT.3 TM-PTO-136L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE			DRAWING	
Amount Due	Date Paid		Sheets Drwg.	Figs. Drwg.
TERMINAL		Primary Examiner	Application Examiner	
DISCLAIMER			PREPARED FOR ISSUE	
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